

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)		ATTY DOCKET NO. 03650.002036		APPLICATION NO. 10/634,755 NYA		
APPLICANT XIAO-CHANG CHARLES LI, et al.		FILING DATE Herewith 8/6/2003		GROUP NYA 1774		
U.S. PATENT DOCUMENTS						
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
DS	U.S. Pub. No. 2001/0031378	10/18/2001	Kreuder, et al.	—	—	—
DS	U.S. Pub. No. 2002/0022150	02/21/2002	Toguchi, et al.	—	—	—
DS	U.S. Pub. No. 2002/0028346	03/07/2002	Shi, et al.	—	—	—
DS	U.S. Pub. No. 2002/0048686	04/25/2002	Suzuki, et al.	—	—	—
DS	U.S. Pub. No. 2002/0048687	04/25/2002	Hosokawa, et al.	—	—	—
DS	U.S. Pub. No. 2002/0048688	04/25/2002	Fukuoka, et al.	—	—	—
DS	U.S. Pub. No. 2002/0055013	05/09/2002	Kim, et al.	—	—	—
DS	U.S. Pub. No. 2002/0061419	05/23/2002	Woo, et al.	—	—	—
DS	U.S. Pub. No. 2002/0061420	05/23/2002	Sohn, et al.	—	—	—
DS	U.S. Pub. No. 2002/0064679	05/30/2002	Ishikawa, et al.	—	—	—
DS	U.S. Pub. No. 2002/0177009	11/28/2002	Suzuki, et al.	—	—	—
FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
DS	2001/192651	07/17/2001	JAPAN	—	—	Abstract
DS	2002/329580	11/15/2002	JAPAN	—	—	Abstract
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)						
EXAMINER			DATE CONSIDERED			
			April 26, 2004			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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DT	2,011,789	08/20/1935	Wulff, et al.	260	168	—
DT	2,109,833	03/01/1938	Zerweck, et al.	260	168	—
DT	2,157,544	05/09/1939	Emil Kline	18	54	—
DT	3,000,984	09/19/1961	André Laurent Halleux	260	668	—
DT	3,549,361	12/22/1970	Jerry B. Miller	96	1.5	—
DT	3,711,567	01/16/1973	John Edwin Innes	260	668	—
DT	4,401,585	08/30/1983	Arthen, Jr. et al.	252	188.3	—
DT	4,956,508	09/11/1990	Michel, et al.	585	26	—
DT	5,059,708	10/22/1991	Aruga, et al.	558	714	—
DT	5,121,029	06/09/1992	Hosokawa, et al.	313	504	—
DT	5,601,903	02/11/1997	Fujii, et al.	428	212	—
DT	5,635,308	06/03/1997	Inoue, et al.	428	690	—
DT	5,728,480	03/17/1998	Stern, et al.	428	690	—
DT	5,759,444	06/02/1998	Enokida, et al.	252	301.16	—
DT	5,811,833	09/22/1998	Mark E. Thompson	257	40	—
DT	5,853,905	12/29/1998	So, et al.	428	690	—
DT	5,858,563	01/12/1999	Sano, et al.	428	690	—
DT	5,858,564	01/12/1999	Tamura, et al.	428	690	—
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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
Def	5,885,498	03/23/1999	Matsuo, et al.	252	583	—	
Def	5,935,721	08/10/1999	Shi, et al.	428	690	—	
Def	5,972,247	10/26/1999	Shi, et al.	252	583	—	
Def	6,004,685	12/21/1999	Antoniadis, et al.	428	690	—	
Def	6,013,383	01/11/2000	Shi, et al.	428	690	—	
Def	6,093,864	07/25/2000	Tokailin, et al.	585	25	—	
Def	6,150,042	11/21/2000	Tamano, et al.	428	690	—	
Def	6,245,449	06/12/2001	Tamano, et al.	428	690	—	
Def	6,251,531	06/26/2001	Enokida, et al.	428	690	—	
Def	6,288,486	09/11/2001	Tsuruoka, et al.	313	504	—	
Def	6,329,083	12/11/2001	Toguchi, et al.	428	690	—	
Def	6,361,885	03/26/2002	Homer Z. Chou	428	690	—	
Def	6,361,886	03/26/2002	Shi, et al.	428	690	—	
Def	6,361,887	03/26/2002	Shi, et al.	428	690	—	

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